

Session Program

Sep 6 – 10, 2026



ENBIS-26 Conference

Measurement Uncertainty and Metrology

Centro Didattico Morgagni
Viale Morgagni 40, Firenze

Wed, September 9

2:30 PM

Measurement Uncertainty and Metrology

Session | Location: Conference Room 106 | Convener: Hichem NOUIRA

2:30 – 2:50 PM

Bias and Multiplicity in Producer Risk Estimation under Simplified Conformity Assessment Models

Speaker

Omar Jair Purata Sifuentes

2:50 – 3:10 PM

A study of prior sensitivity in random effects models for decisions in interlaboratory comparisons: credible intervals versus Bayesian evidence

Speaker

Séverine Demeyer

3:10 – 3:30 PM

An Interactive Software Application for Gauge R&R Analysis

Speaker

Mahmut Onur Karaman

3:30 PM